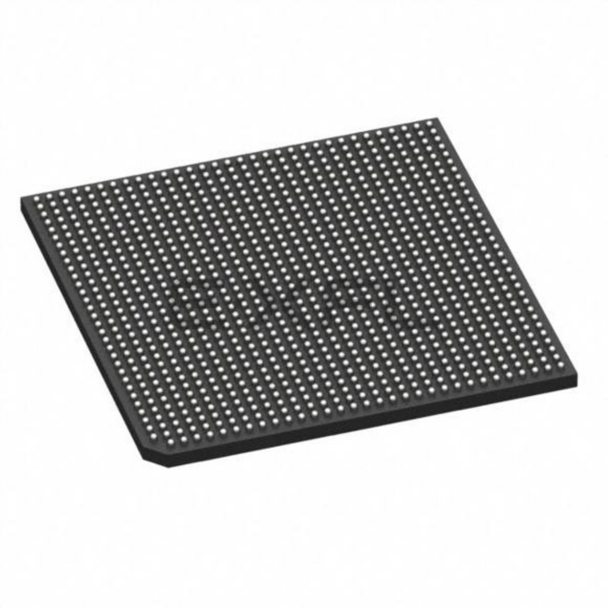

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Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.067GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8572vtarle

2.1.2 Recommended Operating Conditions

Table 2 provides the recommended operating conditions for this device. Note that the values shown are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic		Symbol	Recommended Value	Unit	Notes
Core supply voltage		V_{DD}	1.1 V ± 55 mV	V	—
PLL supply voltage		AV_{DD}	1.1 V ± 55 mV	V	1
Core power supply for SerDes transceivers		SV_{DD}	1.1 V ± 55 mV	V	—
Pad power supply for SerDes transceivers		XV_{DD}	1.1 V ± 55 mV	V	—
DDR SDRAM Controller I/O supply voltage	DDR2 SDRAM Interface	GV_{DD}	1.8 V ± 90 mV	V	—
	DDR3 SDRAM Interface		1.5 V ± 75 mV		—
Three-speed Ethernet I/O voltage		LV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	4
		TV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV		4
DUART, system control and power management, I^2C, and JTAG I/O voltage		OV_{DD}	3.3 V ± 165 mV	V	3
Local bus and GPIO I/O voltage		BV_{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV 1.8 V ± 90 mV	V	—
Input voltage	DDR2 and DDR3 SDRAM Interface signals	MV_{IN}	GND to GV_{DD}	V	2
	DDR2 and DDR3 SDRAM Interface reference	$MV_{REF}n$	$GV_{DD}/2$ ± 1%	V	—
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to LV_{DD} GND to TV_{DD}	V	4
	Local bus and GPIO signals	BV_{IN}	GND to BV_{DD}	V	—
	Local bus, DUART, SYSCLK, Serial RapidIO, system control and power management, I^2C, and JTAG signals	OV_{IN}	GND to OV_{DD}	V	3
Junction temperature range		T_J	0 to 105	°C	—

Notes:

1. This voltage is the input to the filter discussed in Section 21.2.1, “PLL Power Supply Filtering,” and not necessarily the voltage at the AV_{DD} pin, that may be reduced from V_{DD} by the filter.
2. **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
3. **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
4. **Caution:** L/TV_{IN} must not exceed L/TV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.

Table 8. DDRCLK AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
DDRCLK jitter	—	—	—	+/– 150	ps	4, 5, 6

Notes:

1. **Caution:** The DDR complex clock to DDRCLK ratio settings must be chosen such that the resulting DDR complex clock frequency does not exceed the maximum or minimum operating frequencies. Refer to Section 19.4, "DDR/DDRCLK PLL Ratio," for ratio settings.
2. Rise and fall times for DDRCLK are measured at 0.6 V and 2.7 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The DDRCLK driver's closed loop jitter bandwidth should be <500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track DDRCLK drivers with the specified jitter.
6. For spread spectrum clocking, guidelines are +0% to –1% down spread at a modulation rate between 20 kHz and 60 kHz on DDRCLK.

4.5 Platform to eTSEC FIFO Restrictions

Note the following eTSEC FIFO mode maximum speed restrictions based on platform (CCB) frequency.

For FIFO GMII modes (both 8 and 16 bit) and 16-bit encoded FIFO mode:

> FIFO TX/RX clock frequency <= platform clock (CCB) frequency/4.2
>
> For example, if the platform (CCB) frequency is 533 MHz, the FIFO TX/RX clock frequency should be no more than 127 MHz.

For 8-bit encoded FIFO mode:

> FIFO TX/RX clock frequency <= platform clock (CCB) frequency/3.2
>
> For example, if the platform (CCB) frequency is 533 MHz, the FIFO TX/RX clock frequency should be no more than 167 MHz.

4.6 Other Input Clocks

For information on the input clocks of other functional blocks of the platform, such as SerDes and eTSEC, see the respective sections of this document.

5 RESET Initialization

Table 9 describes the AC electrical specifications for the RESET initialization timing.

Table 9. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$	100	—	µs	2
Minimum assertion time for $\overline{\text{SRESET}}$	3	—	SYSCLKs	1

Figure 4 shows the DDR2 and DDR3 SDRAM Interface output timing for the MCK to MDQS skew measurement (tDDKHMH).

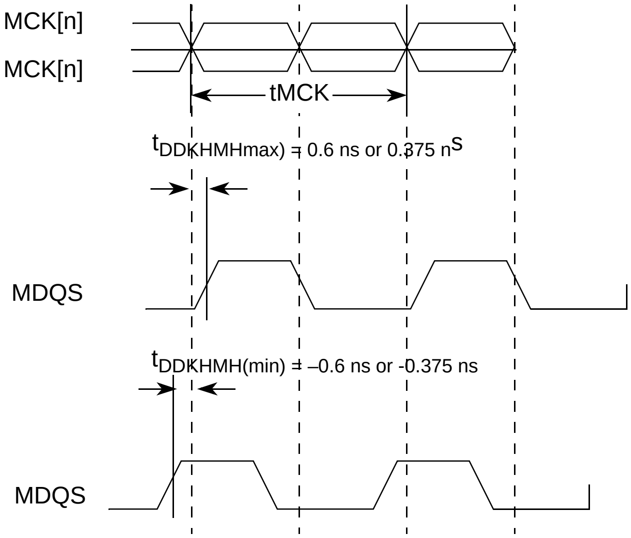

Figure 4. Timing Diagram for tDDKHMH

Figure 5 shows the DDR2 and DDR3 SDRAM Interface output timing diagram.

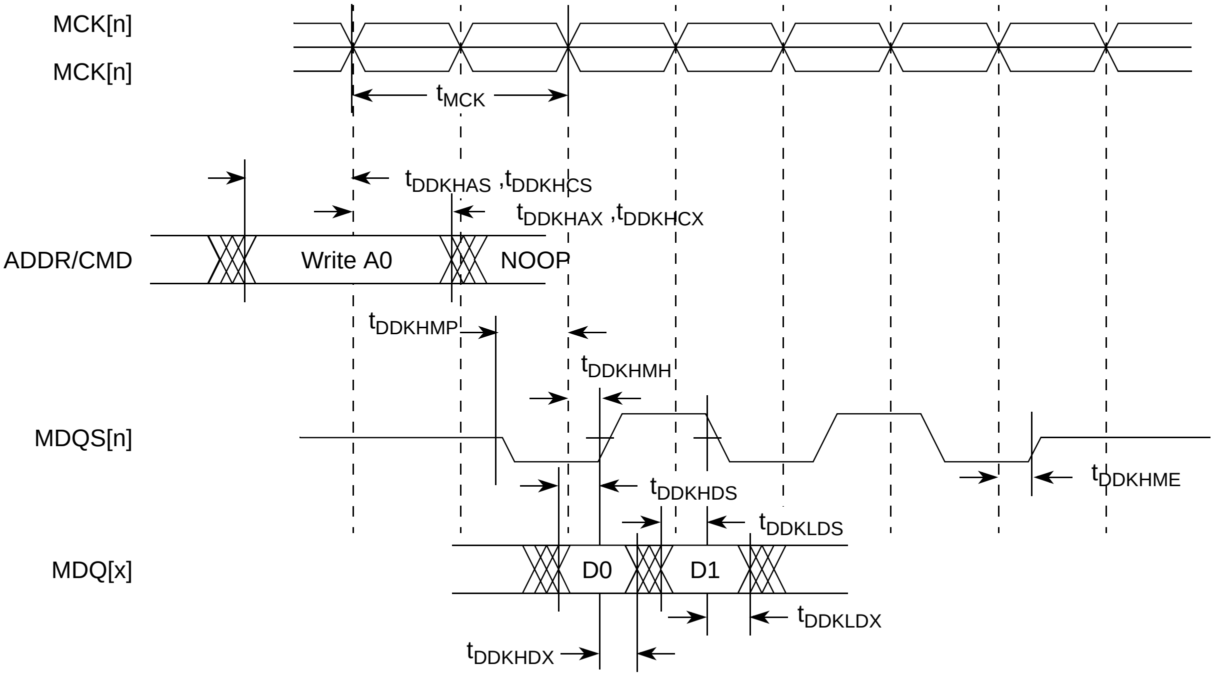

Figure 5. DDR2 and DDR3 SDRAM Interface Output Timing Diagram

Table 24. MII, GMII, RMII, RGMII, TBI, RTBI, and FIFO DC Electrical Characteristics (continued)

Parameters	Symbol	Min	Max	Unit	Notes
Input high current (V_{IN} = LV_{DD}, V_{IN} = TV_{DD})	I_{IH}	—	10	μA	1, 2,3
Input low current (V_{IN} = GND)	I_{IL}	–15	—	μA	3

Note:

[1] LV_{DD} supports eTSECs 1 and 2.
[2] TV_{DD} supports eTSECs 3 and 4 or FEC.
[3] Note that the symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbols referenced in Table 1.

8.2 FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications

The AC timing specifications for FIFO, GMII, MII, TBI, RGMII, RMII and RTBI are presented in this section.

8.2.1 FIFO AC Specifications

The basis for the AC specifications for the eTSEC's FIFO modes is the double data rate RGMII and RTBI specifications, because they have similar performance and are described in a source-synchronous fashion like FIFO modes. However, the FIFO interface provides deliberate skew between the transmitted data and source clock in GMII fashion.

When the eTSEC is configured for FIFO modes, all clocks are supplied from external sources to the relevant eTSEC interface. That is, the transmit clock must be applied to the eTSEC*n*'s TSEC*n*_TX_CLK, while the receive clock must be applied to pin TSEC*n*_RX_CLK. The eTSEC internally uses the transmit clock to synchronously generate transmit data and outputs an echoed copy of the transmit clock back on the TSEC*n*_GTX_CLK pin (while transmit data appears on TSEC*n*_TXD[7:0], for example). It is intended that external receivers capture eTSEC transmit data using the clock on TSEC*n*_GTX_CLK as a source-synchronous timing reference. Typically, the clock edge that launched the data can be used, because the clock is delayed by the eTSEC to allow acceptable set-up margin at the receiver. Note that there is a relationship between the maximum FIFO speed and the platform (CCB) frequency. For more information see Section 4.5, "Platform to eTSEC FIFO Restrictions."

Table 25 and Table 26 summarize the FIFO AC specifications.

Table 25. FIFO Mode Transmit AC Timing Specification

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5V ± 5%

Parameter/Condition	Symbol	Min	Typ	Max	Unit
TX_CLK, GTX_CLK clock period[1]	t_{FIT}	5.3	8.0	100	ns
TX_CLK, GTX_CLK duty cycle	t_{FITH}/t_{FIT}	45	50	55	%

8.3.4 SGMII AC Timing Specifications

This section describes the SGMII transmit and receive AC timing specifications. Transmitter and receiver characteristics are measured at the transmitter outputs (SD2_TX[n] and $\overline{\text{SD2\_TX}}$[n]) or at the receiver inputs (SD2_RX[n] and $\overline{\text{SD2\_RX}}$[n]) as depicted in Figure 25, respectively.

8.3.4.1 SGMII Transmit AC Timing Specifications

Table 40 provides the SGMII transmit AC timing targets. A source synchronous clock is not provided.

Table 40. SGMII Transmit AC Timing Specifications

At recommended operating conditions with XV_{DD_SRDS2} = 1.1V ± 5%.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter	JD	—	—	0.17	UI p-p	—
Total Jitter	JT	—	—	0.35	UI p-p	—
Unit Interval	UI	799.92	800	800.08	ps	1
V_{OD} fall time (80%-20%)	tfall	50	—	120	ps	—
V_{OD} rise time (20%-80%)	t_{rise}	50	—	120	ps	—

Notes:

1. Each UI is 800 ps ± 100 ppm.

8.3.4.2 SGMII Receive AC Timing Specifications

Table 41 provides the SGMII receive AC timing specifications. Source synchronous clocking is not supported. Clock is recovered from the data. Figure 24 shows the SGMII receiver input compliance mask eye diagram.

Table 41. SGMII Receive AC Timing Specifications

At recommended operating conditions with XV_{DD_SRDS2} = 1.1V ± 5%.

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Deterministic Jitter Tolerance	JD	0.37	—	—	UI p-p	1
Combined Deterministic and Random Jitter Tolerance	JDR	0.55	—	—	UI p-p	1
Sinusoidal Jitter Tolerance	JSIN	0.1	—	—	UI p-p	1
Total Jitter Tolerance	JT	0.65	—	—	UI p-p	1
Bit Error Ratio	BER	—	—	10^{-12}	—	—
Unit Interval	UI	799.92	800	800.08	ps	2
AC Coupling Capacitor	C_{TX}	5	—	200	nF	3

Notes:

1. Measured at receiver.
2. Each UI is 800 ps ± 100 ppm.
3. The external AC coupling capacitor is required. It is recommended to be placed near the device transmitter outputs.
4. See *RapidIO 1x/4x LP Serial Physical Layer Specification* for interpretation of jitter specifications.

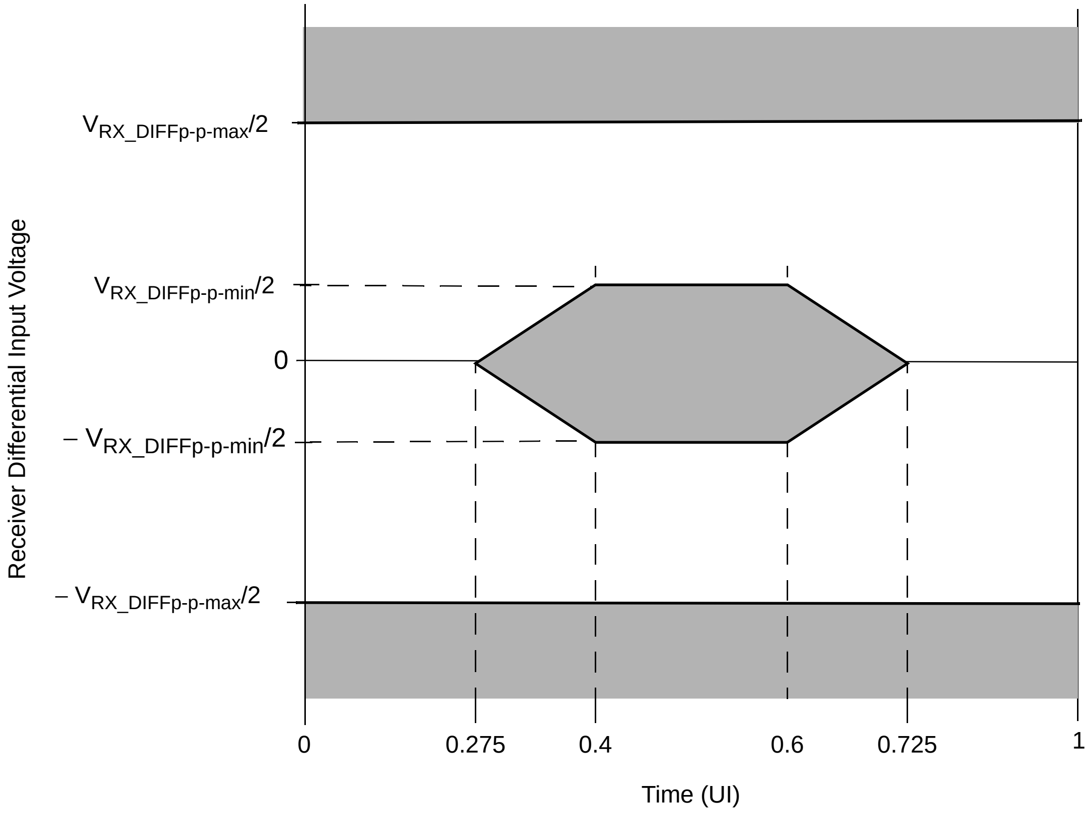

Figure 24. SGMII Receiver Input Compliance Mask

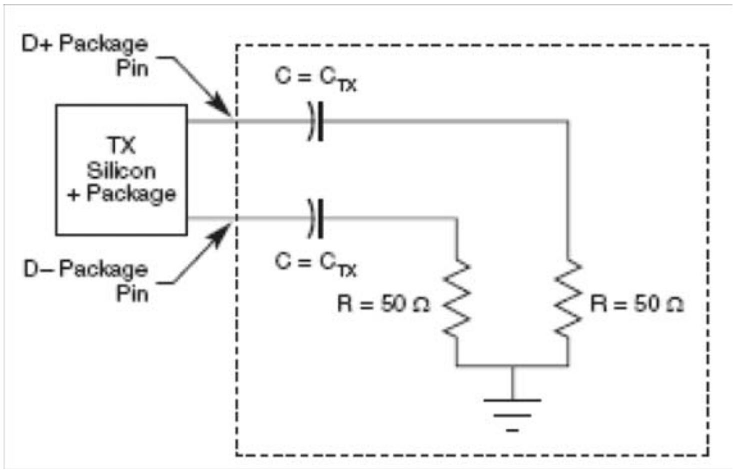

Figure 25. SGMII AC Test/Measurement Load

Table 43. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=3.3 V) (continued)

Parameter	Symbol	Min	Max	Unit	Notes
Input low current (LV_{DD}/TV_{DD} = Max, V_{IN} = 0.5 V)	I_{IL}	–600	—	µA	—

Note:

1. EC1_MDC and EC1_MDIO operate on LV_{DD}.
2. EC3_MDC & EC3_MDIO and EC5_MDC & EC5_MDIO operate on TV_{DD}.
3. Note that the symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbol referenced in Table 1.

Table 44. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=2.5 V)

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	LV_{DD}/TV_{DD}	2.37	2.63	V	1,2
Output high voltage (LV_{DD}/TV_{DD} = Min, IOH = –1.0 mA)	V_{OH}	2.00	LV_{DD}/TV_{DD} + 0.3	V	—
Output low voltage (LV_{DD}/TV_{DD} = Min, I_{OL} = 1.0 mA)	V_{OL}	GND – 0.3	0.40	V	—
Input high voltage	V_{IH}	1.70	LV_{DD}/TV_{DD} + 0.3	V	—
Input low voltage	V_{IL}	–0.3	0.70	V	—
Input high current (V_{IN} = LV_{DD}, V_{IN} = TV_{DD})	I_{IH}	—	10	µA	1, 2,3
Input low current (V_{IN} = GND)	I_{IL}	–15	—	µA	3

Note:

[1] EC1_MDC and EC1_MDIO operate on LV_{DD}.

[2] EC3_MDC & EC3_MDIO and EC5_MDC & EC5_MDIO operate on TV_{DD}.

[3] Note that the symbol V_{IN}, in this case, represents the LV_{IN} and TV_{IN} symbols referenced in Table 1.

9.2 MII Management AC Electrical Specifications

Table 45 provides the MII management AC timing specifications.There are three sets of Ethernet management signals (EC1_MDC and EC1_MDIO, EC3_MDC and EC3_MDIO, EC5_MDC and EC5_MDIO). These are not explicitly shown in the table or in the figure following.

Table 45. MII Management AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
ECn_MDC frequency	f_{MDC}	0.9	2.5	9.3	MHz	2, 3
ECn_MDC period	t_{MDC}	107.5	—	1120	ns	—
ECn_MDC clock pulse width high	t_{MDCH}	32	—	—	ns	—
ECn_MDC to ECn_MDIO delay	t_{MDKHDX}	10	—	16*t_{plb_clk}	ns	5

Table 51. Local Bus General Timing Parameters (BV_{DD} = 1.8 V DC)—PLL Enabled (continued)

At recommended operating conditions with BV_{DD} of 1.8 V ± 5% (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{LGTA}}$/LUPWAIT input hold from local bus clock	$t_{LBIXKH2}$	1.1	—	ns	3, 4
LALE output negation to high impedance for LAD/LDP (LATCH hold time)	t_{LBOTOT}	1.2	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKHOV1}$	—	3.2	ns	—
Local bus clock to data valid for LAD/LDP	$t_{LBKHOV2}$	—	3.2	ns	3
Local bus clock to address valid for LAD	$t_{LBKHOV3}$	—	3.2	ns	3
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	3.2	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.9	—	ns	3
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.9	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.6	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.6	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 1.8-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 29 provides the AC test load for the local bus.

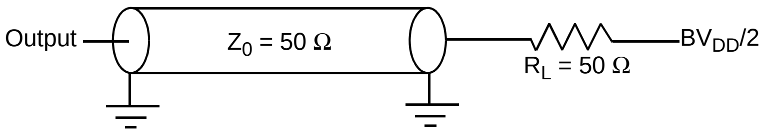

Figure 29. Local Bus AC Test Load

Table 58 provides the DC electrical characteristics for the GPIO interface operating at BV_{DD} = 1.8 V DC.

Table 58. GPIO DC Electrical Characteristics (1.8 V DC)

Parameter	Symbol	Min	Max	Unit
Supply voltage 1.8V	BV_{DD}	1.71	1.89	V
High-level input voltage	V_{IH}	0.65 x BV_{DD}	BV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.35 x BV_{DD}	V
Input current (BV_{IN} [1] = 0 V or BV_{IN} = BV_{DD})	I_{IN}	TBD	TBD	μA
High-level output voltage (I_{OH} = –100 μA)	V_{OH}	BV_{DD} – 0.2	—	V
High-level output voltage (I_{OH} = –2 mA)	V_{OH}	BV_{DD} – 0.45	—	V
Low-level output voltage (I_{OL} = 100 μA)	V_{OL}	—	0.2	V
Low-level output voltage (I_{OL} = 2 mA)	V_{OL}	—	0.45	V

Note:

1. The symbol BV_{IN}, in this case, represents the BV_{IN} symbol referenced in Table 1.

14.2 GPIO AC Electrical Specifications

Table 59 provides the GPIO input and output AC timing specifications.

Table 59. GPIO Input AC Timing Specifications[1]

Parameter	Symbol	Typ	Unit	Notes
GPIO inputs—minimum pulse width	t_{PIWID}	20	ns	2

Notes:

1. Input specifications are measured from the 50% level of the signal to the 50% level of the rising edge of SYSCLK. Timings are measured at the pin.
2. GPIO inputs and outputs are asynchronous to any visible clock. GPIO outputs should be synchronized before use by any external synchronous logic. GPIO inputs are required to be valid for at least t_{PIWID} ns to ensure proper operation.

Figure 42 provides the AC test load for the GPIO.

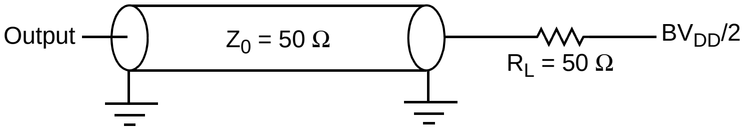

Figure 42. GPIO AC Test Load

— To meet the input amplitude requirement, the reference clock inputs might need to be DC or AC-coupled externally. For the best noise performance, the reference of the clock could be DC or AC-coupled into the unused phase ($\overline{\mathrm{SD}n\mathrm{\_REF\_CLK}}$) through the same source impedance as the clock input (SD*n*_REF_CLK) in use.

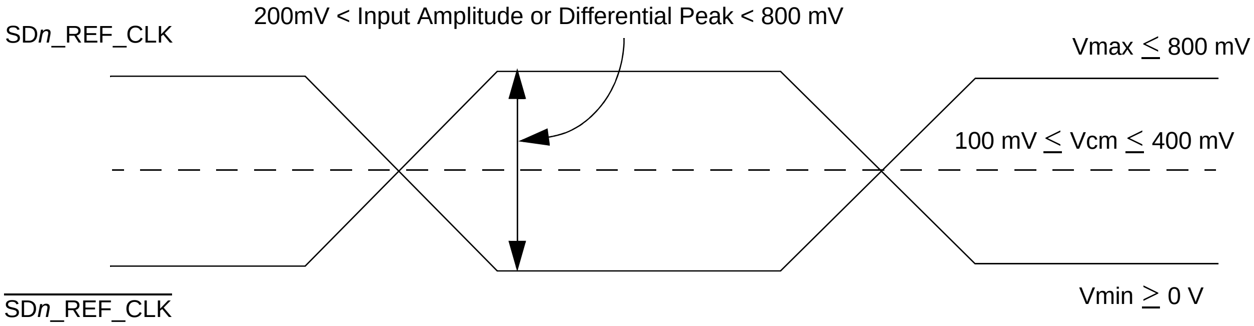

Figure 45. Differential Reference Clock Input DC Requirements (External DC-Coupled)

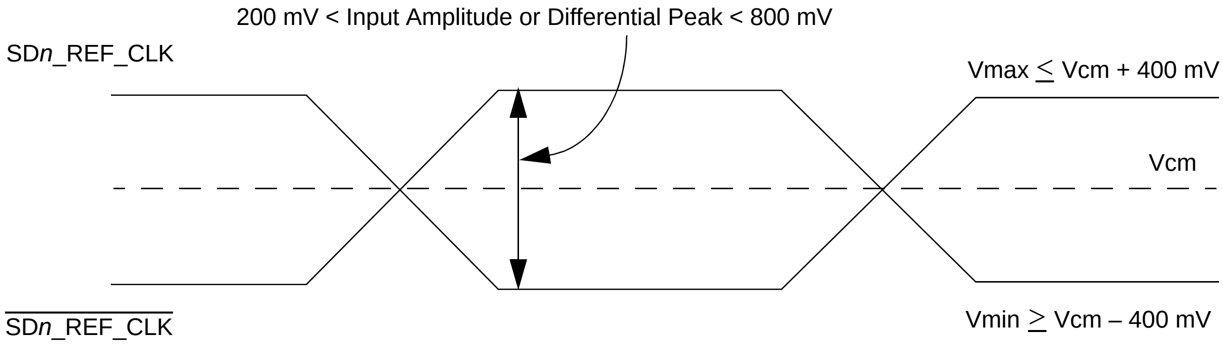

Figure 46. Differential Reference Clock Input DC Requirements (External AC-Coupled)

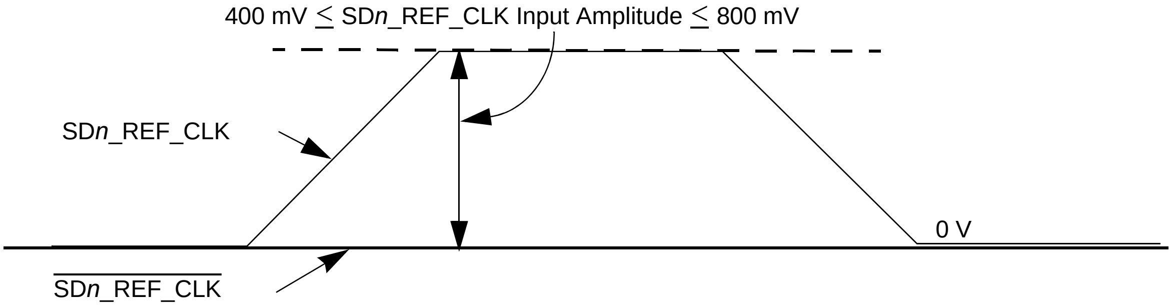

Figure 47. Single-Ended Reference Clock Input DC Requirements

Figure 49 shows the SerDes reference clock connection reference circuits for LVDS type clock driver. Because LVDS clock driver's common mode voltage is higher than the MPC8572E SerDes reference clock input's allowed range (100 to 400mV), AC-coupled connection scheme must be used. It assumes the LVDS output driver features 50-Ω termination resistor. It also assumes that the LVDS transmitter establishes its own common mode level without relying on the receiver or other external component.

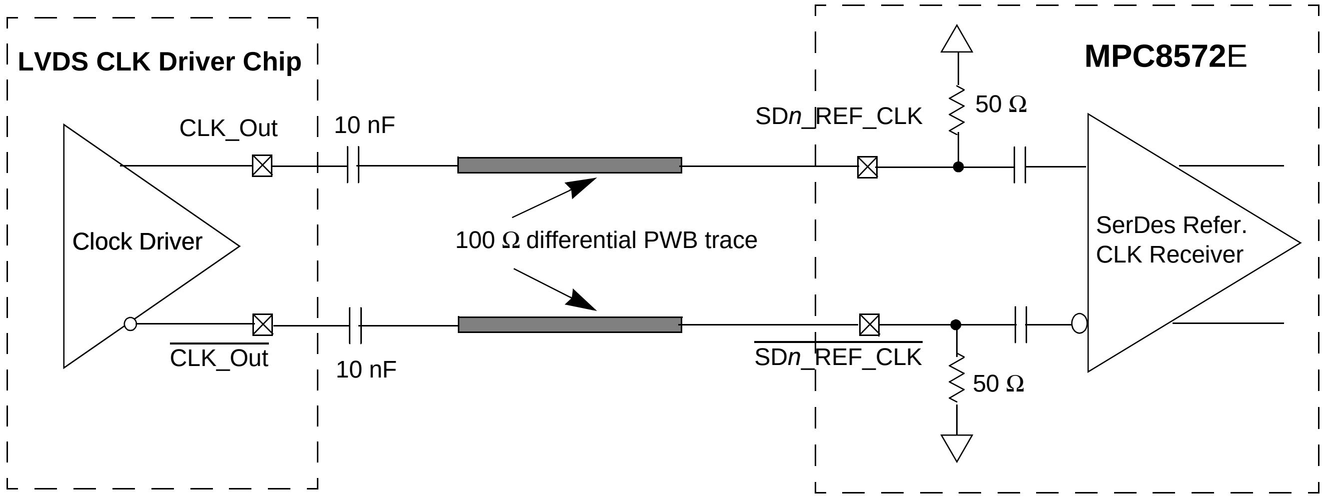

Figure 49. AC-Coupled Differential Connection with LVDS Clock Driver (Reference Only)

Figure 50 shows the SerDes reference clock connection reference circuits for LVPECL type clock driver. Because LVPECL driver's DC levels (both common mode voltages and output swing) are incompatible with MPC8572E SerDes reference clock input's DC requirement, AC-coupling must be used. Figure 50 assumes that the LVPECL clock driver's output impedance is 50Ω. R1 is used to DC-bias the LVPECL outputs prior to AC-coupling. Its value could be ranged from 140Ω to 240Ω depending on clock driver vendor's requirement. R2 is used together with the SerDes reference clock receiver's 50-Ω termination resistor to attenuate the LVPECL output's differential peak level such that it meets the MPC8572E SerDes reference clock's differential input amplitude requirement (between 200mV and 800mV differential peak). For example, if the LVPECL output's differential peak is 900mV and the desired SerDes reference clock input amplitude is selected as 600mV, the attenuation factor is 0.67, which requires R2 = 25Ω. Consult

16.5 Receiver Compliance Eye Diagrams

The RX eye diagram in Figure 56 is specified using the passive compliance/test measurement load (see Figure 57) in place of any real PCI Express RX component.

Note: In general, the minimum Receiver eye diagram measured with the compliance/test measurement load (see Figure 57) is larger than the minimum Receiver eye diagram measured over a range of systems at the input Receiver of any real PCI Express component. The degraded eye diagram at the input Receiver is due to traces internal to the package as well as silicon parasitic characteristics which cause the real PCI Express component to vary in impedance from the compliance/test measurement load. The input Receiver eye diagram is implementation specific and is not specified. RX component designer should provide additional margin to adequately compensate for the degraded minimum Receiver eye diagram (shown in Figure 56) expected at the input Receiver based on some adequate combination of system simulations and the Return Loss measured looking into the RX package and silicon. The RX eye diagram must be aligned in time using the jitter median to locate the center of the eye diagram.

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50. probes—see Figure 57). Note that the series capacitors, CTX, are optional for the return loss measurement.

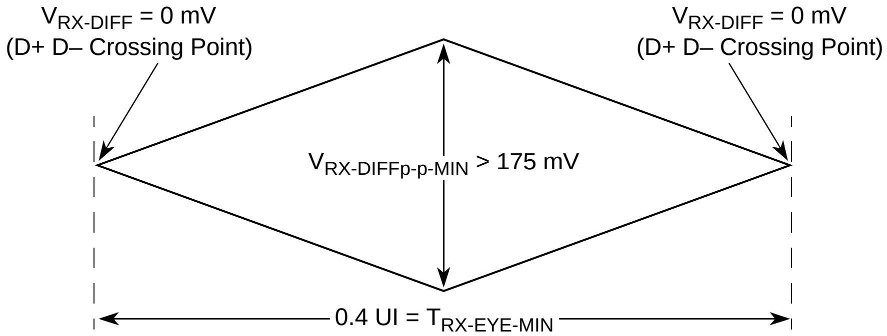

Figure 56. Minimum Receiver Eye Timing and Voltage Compliance Specification

17.1 DC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

For more information, see Section 15.2, “SerDes Reference Clocks.”

17.2 AC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

Figure 64lists the AC requirements.

Table 64. SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ AC Requirements

Symbol	Parameter Description	Min	Typical	Max	Units	Comments
t_{REF}	REFCLK cycle time	—	10(8)	—	ns	8 ns applies only to serial RapidIO with 125-MHz reference clock
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	80	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	–40	—	40	ps	—

17.3 Equalization

With the use of high speed serial links, the interconnect media causes degradation of the signal at the receiver. Effects such as Inter-Symbol Interference (ISI) or data dependent jitter are produced. This loss can be large enough to degrade the eye opening at the receiver beyond what is allowed in the specification. To negate a portion of these effects, equalization can be used. The most common equalization techniques that can be used are as follows:

- A passive high pass filter network placed at the receiver. This is often referred to as passive equalization.
- The use of active circuits in the receiver. This is often referred to as adaptive equalization.

17.4 Explanatory Note on Transmitter and Receiver Specifications

AC electrical specifications are given for transmitter and receiver. Long run and short run interfaces at three baud rates (a total of six cases) are described.

The parameters for the AC electrical specifications are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002.

XAUI has similar application goals to serial RapidIO, as described in Section 8.1, “Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—FIFO/GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics.” The goal of this standard is that electrical designs for Serial RapidIO can reuse electrical designs for XAUI, suitably modified for applications at the baud intervals and reaches described herein.

Table 66. Short Run Transmitter AC Timing Specifications—2.5 GBaud (continued)

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Multiple Output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	400	400	ps	+/- 100 ppm

Table 67. Short Run Transmitter AC Timing Specifications—3.125 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage,	V_O	–0.40	2.30	Volts	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	500	1000	mV p-p	—
Deterministic Jitter	J_D	—	0.17	UI p-p	—
Total Jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	320	320	ps	+/– 100 ppm

Table 68. Long Run Transmitter AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output Voltage,	V_O	–0.40	2.30	Volts	Voltage relative to COMMON of either signal comprising a differential pair
Differential Output Voltage	V_{DIFFPP}	800	1600	mV p-p	—
Deterministic Jitter	J_D	—	0.17	UI p-p	—
Total Jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	800	800	ps	+/- 100 ppm

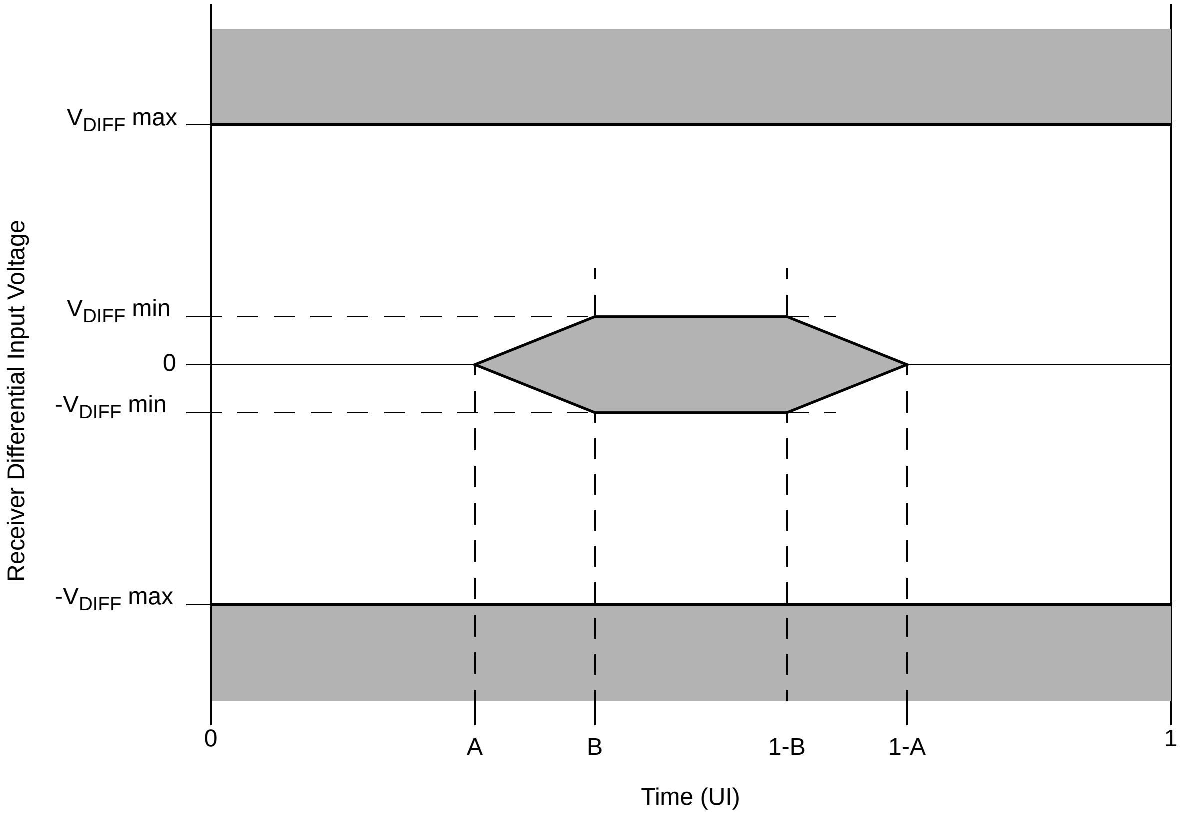

Figure 60. Receiver Input Compliance Mask

Table 75. Receiver Input Compliance Mask Parameters Exclusive of Sinusoidal Jitter

Receiver Type	V_{DIFF}min (mV)	V_{DIFF}max (mV)	A (UI)	B (UI)
1.25 GBaud	100	800	0.275	0.400
2.5 GBaud	100	800	0.275	0.400
3.125 GBaud	100	800	0.275	0.400

17.8 Measurement and Test Requirements

Because the LP-Serial electrical specification are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002, the measurement and test requirements defined here are similarly guided by Clause 47. Additionally, the CJPAT test pattern defined in Annex 48A of IEEE 802.3ae-2002 is specified as the test pattern for use in eye pattern and jitter measurements. Annex 48B of IEEE 802.3ae-2002 is recommended as a reference for additional information on jitter test methods.

17.8.1 Eye Template Measurements

For the purpose of eye template measurements, the effects of a single-pole high pass filter with a 3 dB point at (Baud Frequency)/1667 is applied to the jitter. The data pattern for template measurements is the Continuous Jitter Test Pattern (CJPAT) defined in Annex 48A of IEEE 802.3ae. All lanes of the LP-Serial

Table 81 describes the clock ratio between e500 Core1 and the e500 core complex bus (CCB). This ratio is determined by the binary value of $\overline{\text{LWE}}$[0]/LBS[0]/LFWE, UART_SOUT[1], and READY_P1 signals at power up, as shown in Table 81.

Table 81. e500 Core1 to CCB Clock Ratio

Binary Value of $\overline{\text{LWE}}$[0]/LBS[0]/ LFWE, UART_SOUT[1], READY_P1 Signals	e500 Core1:CCB Clock Ratio	Binary Value of $\overline{\text{LWE}}$[0]/LBS[0]/ LFWE, UART_SOUT[1], READY_P1 Signals	e500 Core1:CCB Clock Ratio
000	Reserved	100	2:1
001	Reserved	101	5:2 (2.5:1)
010	Reserved	110	3:1
011	3:2 (1.5:1)	111	7:2 (3.5:1)

19.4 DDR/DDRCLK PLL Ratio

The dual DDR memory controller complexes can be synchronous with, or asynchronous to, the CCB, depending on configuration.

Table 82 describes the clock ratio between the DDR memory controller complexes and the DDR PLL reference clock, DDRCLK, which is not the memory bus clock. The DDR memory controller complexes clock frequency is equal to the DDR data rate.

When synchronous mode is selected, the memory buses are clocked at half the CCB clock rate. The default mode of operation is for the DDR data rate for both DDR controllers to be equal to the CCB clock rate in synchronous mode, or the resulting DDR PLL rate in asynchronous mode.

In asynchronous mode, the DDR PLL rate to DDRCLK ratios listed in Table 82 reflects the DDR data rate to DDRCLK ratio, because the DDR PLL rate in asynchronous mode means the DDR data rate resulting from DDR PLL output.

Note that the DDR PLL reference clock input, DDRCLK, is only required in asynchronous mode. MPC8572E does not support running one DDR controller in synchronous mode and the other in asynchronous mode.

Table 82. DDR Clock Ratio

Binary Value of TSEC_1588_CLK_OUT, TSEC_1588_PULSE_OUT1, TSEC_1588_PULSE_OUT2 Signals	DDR:DDRCLK Ratio
000	3:1
001	4:1
010	6:1
011	8:1
100	10:1

Table 82. DDR Clock Ratio (continued)

Binary Value of TSEC_1588_CLK_OUT, TSEC_1588_PULSE_OUT1, TSEC_1588_PULSE_OUT2 Signals	DDR:DDRCLK Ratio
101	12:1
110	14:1
111	Synchronous mode

19.5 Frequency Options

19.5.1 Platform to Sysclk Frequency Options

Table 83 shows the expected frequency values for the platform frequency when using the specified CCB clock to SYSCLK ratio.

Table 83. Frequency Options for Platform Frequency

CCB to SYSCLK Ratio	SYSCLK (MHz)							
	33.33	**41.66**	**50**	**66.66**	**83**	**100**	**111**	**133.33**
	Platform /CCB Frequency (MHz)							
4						400	444	533
5					415	500	555	
6				400	498	600		
8			400	533				
10		417	500					
12	400	500	600					

19.5.2 Minimum Platform Frequency Requirements for High-Speed Interfaces

Section 4.4.3.6, “I/O Port Selection,” in the *MPC8572E PowerQUICC III Integrated Host Processor Family Reference Manual* describes various high-speed interface configuration options. Note that the CCB clock frequency must be considered for proper operation of such interfaces as described below.

For proper PCI Express operation, the CCB clock frequency must be greater than or equal to:

$$\frac{527\text{ MHz} \times (\text{PCI Express link width})}{8}$$

See Section 21.1.3.2, “Link Width,” in the *MPC8572E PowerQUICC III Integrated Host Processor Family Reference Manual* for PCI Express interface width details. Note that the “PCI Express link width”

Table 85 summarizes the signal impedance targets. The driver impedances are targeted at minimum V_{DD}, nominal OV_{DD}, 105°C.

Table 85. Impedance Characteristics

Impedance	Local Bus, Ethernet, DUART, Control, Configuration, Power Management	DDR DRAM	Symbol	Unit
R_N	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z_0	Ω
R_P	45 Target	18 Target (full strength mode) 36 Target (half strength mode)	Z_0	Ω

Note: Nominal supply voltages. See Table 1, T_j = 105°C.

21.8 Configuration Pin Muxing

The MPC8572E provides the user with power-on configuration options which can be set through the use of external pull-up or pull-down resistors of 4.7 kΩ on certain output pins (see customer visible configuration pins). These pins are generally used as output only pins in normal operation.

While $\overline{\text{HRESET}}$ is asserted however, these pins are treated as inputs. The value presented on these pins while $\overline{\text{HRESET}}$ is asserted, is latched when $\overline{\text{HRESET}}$ deasserts, at which time the input receiver is disabled and the I/O circuit takes on its normal function. Most of these sampled configuration pins are equipped with an on-chip gated resistor of approximately 20 kΩ. This value should permit the 4.7-kΩ resistor to pull the configuration pin to a valid logic low level. The pull-up resistor is enabled only during $\overline{\text{HRESET}}$ (and for platform /system clocks after $\overline{\text{HRESET}}$ deassertion to ensure capture of the reset value). When the input receiver is disabled the pull-up is also, thus allowing functional operation of the pin as an output with minimal signal quality or delay disruption. The default value for all configuration bits treated this way has been encoded such that a high voltage level puts the device into the default state and external resistors are needed only when non-default settings are required by the user.

Careful board layout with stubless connections to these pull-down resistors coupled with the large value of the pull-down resistor should minimize the disruption of signal quality or speed for output pins thus configured.

The platform PLL ratio, DDR complex PLL and e500 PLL ratio configuration pins are not equipped with these default pull-up devices.

21.9 JTAG Configuration Signals

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 66. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE Std 1149.1 specification, but it is provided on all processors built on Power Architecture technology. The device requires $\overline{\text{TRST}}$ to be asserted during power-on reset flow to ensure that the JTAG boundary

21.10.3 SerDes 2 Interface (SGMII) Entirely Unused

If the high-speed SerDes 2 interface (SGMII) is not used at all, the unused pin should be terminated as described in this section.

The following pins must be left unconnected (float):

- SD2_TX[3:0]
- $\overline{\text{SD2\_TX}}$[3:0]
- Reserved pins: AF26, AF27

The following pins must be connected to XGND_SRDS2:

- SD2_RX[3:0]
- $\overline{\text{SD2\_RX}}$[3:0]
- SD2_REF_CLK
- $\overline{\text{SD2\_REF\_CLK}}$

The POR configuration pin cfg_srds_sgmii_en on $\overline{\text{UART\_RTS}}$[1] can be used to power down SerDes 2 block for power saving. Note that both SVDD_SRDS2 and XVDD_SRDS2 must remain powered.

21.10.4 SerDes 2 Interface (SGMII) Partly Unused

If only part of the high speed SerDes 2 interface (SGMII) pins are used, the remaining high-speed serial I/O pins should be terminated as described in this section.

The following pins must be left unconnected (float):

- SD2_TX[3:0]
- $\overline{\text{SD2\_TX}}$[3:0]
- Reserved pins: AF26, AF27

The following pins must be connected to XGND_SRDS2:

- SD2_RX[3:0]
- $\overline{\text{SD2\_RX}}$[3:0]

22 Ordering Information

Ordering information for the parts fully covered by this specification document is provided in Section 22.1, “Part Numbers Fully Addressed by this Document.”

22.1 Part Numbers Fully Addressed by this Document

Table 86 through Table 88 provide the Freescale part numbering nomenclature for the MPC8572E. Note that the individual part numbers correspond to a maximum processor core frequency. For available frequencies, contact your local Freescale sales office. In addition to the processor frequency, the part numbering scheme also includes an application modifier which may specify special application conditions. Each part number also contains a revision code which refers to the die mask revision number.

Table 86. Part Numbering Nomenclature—Rev 2.2.1

MPC	***nnnn***	***e***	***t***	***l***	***pp***	***ffm***	***r***
Product Code[1]	**Part Identifier**	**Security Engine**	**Temperature**	**Power**	**Package Sphere Type**[2]	**Processor Frequency/ DDR Data Rate**[3]	**Silicon Revision**
MPC PPC	8572	E = Included	Blank = 0 to 105°C C = –40 to 105°C	Blank = Standard L = Low	PX = Leaded, FC-PBGA VT = Pb-free, FC-PBGA[4] VJ = Fully Pb-free FC-PBGA[5]	AVN = 1500-MHz processor; 800 MT/s DDR data rate AUL = 1333-MHz processor; 667 MT/s DDR data rate ATL = 1200-MHz processor; 667 MT/s DDR data rate ARL = 1067-MHz processor; 667 MT/s DDR data rate	E = Ver. 2.2.1 (SVR = 0x80E8_0022) SEC included
		Blank = Not included					E = Ver. 2.2.1 (SVR = 0x80E0_0022) SEC not included

Notes:

[1] MPC stands for “Qualified.”
PPC stands for “Prototype”

[2] See Section 18, “Package Description,” for more information on the available package types.

[3] Processor core frequencies supported by parts addressed by this specification only. Not all parts described in this specification support all core frequencies. Additionally, parts addressed by part number specifications may support other maximum core frequencies.

4. The VT part number is ROHS-compliant with the permitted exception of the C4 die bumps.

5. The VJ part number is entirely lead-free. This includes the C4 die bumps.